

61 AF IFW



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2895
Examiner: Swapneel CHHAYA

In Re PATENT APPLICATION of:

Applicant(s):	Takamitsu YAMANAKA)	
U.S. Serial No.:	10/577,457)	
U.S. Filing Date:	April 27, 2006)	
International Serial No.:	PCT/JP2005/014208)	
International Filing Date:	August 3, 2005)	<u>AMENDMENT</u>
Priority Date Claimed:	August 17, 2004)	
For:	SEMICONDUCTOR DEVICE AND ITS MANUFACTURING METHOD)	
Attorney Reference:	AI 409NP)	

September 24, 2009

/Swapneel Chhaya/ 10/08/2009
Do not enter

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Examiner's Action mailed on June 24, 2009, please
amend the above-identified application as follows: